

ADOPTION NOTICE

ASTM F1192, "Measurement of Single Event Phenomena (SEP) Induced by Heavy Ion Irradiation of Semiconductor Devices [Metric]" was adopted on 14 July 1999 for use by the Department of Defense (DoD). Proposed changes by DoD activities must be submitted to the DoD Adopting Activity: Defense Supply Center, Columbus, Attn: DSCC-VAC, 3990 E. Broad St., Columbus, OH 43216-5000. DoD activities may obtain copies of this standard from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094. The private sector and other Government agencies may purchase copies from the American Society for Testing and Materials, 100 Barr Harbor Drive, West Conshohocken, PA 19428-2959.

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